

## Silicon Carbide Enhancement Mode MOSFET

### Features

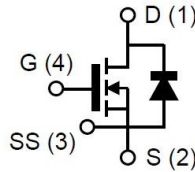
- High blocking voltage with low  $R_{DS(on)}$
- High frequency operation with low Capacitance
- Simple to drive with -4V/+15V gate
- Robust body diode with low  $Q_{rr}$
- 100% Avalanche Tested

### Benefits

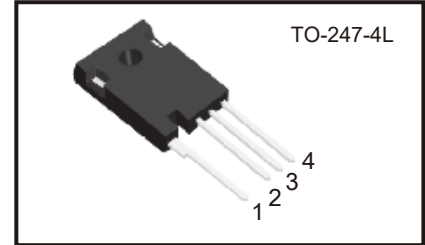
- Superior robustness and system reliability
- Higher system efficiency
- Easier paralleling without thermal runaway
- Capable of high temperature application
- Faster and more efficient switching

### Applications

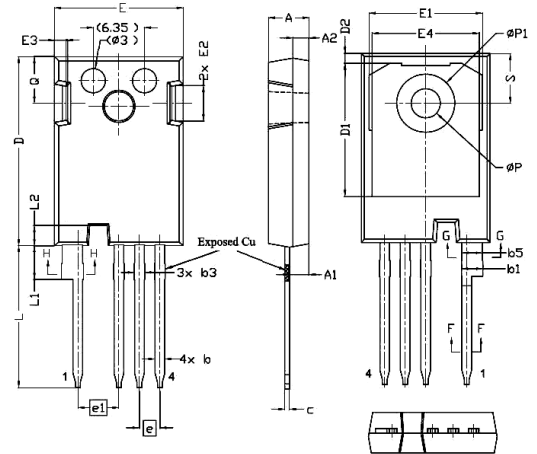
- EV motor drives
- EV/HEV charging station
- Energy storage and Battery charging
- High voltage DC-DC converters
- Solar / Wind Inverters
- UPS and PFC



|                     |                |
|---------------------|----------------|
| $V_{DSS}$           | 1200V          |
| $I_D(@25^{\circ}C)$ | 155A           |
| $R_{DS(ON)}$        | 14.5m $\Omega$ |



Package Dimensions



### Absolute Maximum Ratings

( $T_c = 25^{\circ}C$  unless otherwise specified)

| Parameter   | Symbol        | Ratings     | Unit        |
|---|---------------|-------------|-------------|
| Drain-Source Voltage<br>$V_{GS}=0V$<br>$I_D=100\mu A$                                     | $V_{DS}$      | 1200        | V           |
| Gate-Source Voltage (dynamic)<br>AC ( $f>1$ Hz,<br>duty cycle<1%,<br>pulse width<200ns)   | $V_{GS}$      | -8/+19      | V           |
| Gate-Source Voltage (static)  | $V_{GS(op)}$  | -4/+15      | V           |
| Drain Current-Continuous<br>$V_{GS}=18V@T_c=25^{\circ}C$<br>$V_{GS}=18V@T_c=100^{\circ}C$ | $I_D$         | 155<br>110  | A           |
| Pulse Drain Current   | $I_{D,pulse}$ | 313         | A           |
| Power Dissipation   | $P_D$         | 652         | W           |
| Storage Temperature Range   | $T_{STG}$     | -55 to +175 | $^{\circ}C$ |
| Operating Junction Temperature Range  | $T_J$         | -55 to +175 | $^{\circ}C$ |
| Soldering Temperature   | $T_L$         | 260         | $^{\circ}C$ |
| Avalanche Capability, single pulse *<br>$V_{DD}=100V$<br>$V_{GS}=15V$<br>$L=2mH$          | $I_{AV}$      | 55          | A           |
| Avalanche Capability, single pulse**<br>$V_{DD}=100V$<br>$V_{GS}=15V$<br>$L=2mH$          | $E_{AV}$      | 3025        | mJ          |

\* 100% tested in 60% rating

\*\* 100% tested in 36% rating

| SYMBOL | DIMENSIONS |       |       |
|--------|------------|-------|-------|
|        | MIN.       | NOM.  | MAX.  |
| A      | 4.83       | 5.02  | 5.21  |
| A1     | 2.29       | 2.41  | 2.54  |
| A2     | 1.91       | 2.00  | 2.16  |
| b'     | 1.07       | 1.20  | 1.28  |
| b      | 1.07       | 1.20  | 1.33  |
| b1     | 2.39       | 2.67  | 2.94  |
| b2     | 2.39       | 2.67  | 2.84  |
| b3     | 1.07       | 1.30  | 1.60  |
| b4     | 1.07       | 1.30  | 1.50  |
| b5     | 2.39       | 2.53  | 2.69  |
| b6     | 2.39       | 2.53  | 2.64  |
| c      | 0.55       | 0.60  | 0.68  |
| c1     | 0.55       | 0.60  | 0.65  |
| D      | 23.30      | 23.45 | 23.60 |
| D1     | 16.25      | 16.55 | 17.65 |
| D2     | 0.95       | 1.19  | 1.25  |

| SYMBOL    | DIMENSIONS |       |       |
|-----------|------------|-------|-------|
|           | MIN.       | NOM.  | MAX.  |
| E         | 15.75      | 15.94 | 16.13 |
| E1        | 13.10      | 14.02 | 14.15 |
| E2        | 3.68       | 4.40  | 5.10  |
| E3        | 1.00       | 1.45  | 1.90  |
| E4        | 12.38      | 13.26 | 13.43 |
| e         | 2.54 BSC   |       |       |
| e1        | 5.08 BSC   |       |       |
| L         | 17.31      | 17.57 | 17.82 |
| L1        | 3.97       | 4.19  | 4.37  |
| L2        | 2.35       | 2.50  | 2.65  |
| $\phi P$  | 3.51       | 3.61  | 3.65  |
| $\phi P1$ | 7.19 REF.  |       |       |
| Q         | 5.49       | 5.79  | 6.00  |
| S         | 6.04       | 6.17  | 6.30  |

**Electrical Characteristics @ T<sub>c</sub> =25°C (unless otherwise specified)**

| Parameter                            | Symbol               | Conditions   | Min. | Typ. | Max. | Unit |
|--------------------------------------|----------------------|--|------|------|------|------|
| OFF Characteristics                  |                      |  |      |      |      |      |
| Drain-Source Breakdown Voltage       | BV <sub>DSS</sub>    | V <sub>GS</sub> =0V , I <sub>D</sub> =0.1mA  | 1200 | -    | -    | V    |
| Zero Gate Voltage Drain Current      | I <sub>DSS</sub>     | V <sub>GS</sub> =0V , V <sub>DS</sub> =1200V   | -    | 0.5  | 60   | μA   |
| Gate-Source Leakage Current          | I <sub>GSS</sub>     | V <sub>GS</sub> =15V , V <sub>DS</sub> =0V   | -    | 5    | 100  | nA   |
| ON Characteristics                   |                      |  |      |      |      |      |
| Gate Threshold Voltage               | V <sub>GS(th)</sub>  | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =30mA   | 1.8  | 2.5  | 3.2  | V    |
| Drain-Source On-State Resistance     | R <sub>DS(on)</sub>  | V <sub>GS</sub> =15V , I <sub>D</sub> =75A   | -    | 14.5 | 19   | mΩ   |
| Transconductance                     | g <sub>fs</sub>      | V <sub>DS</sub> =20V , I <sub>D</sub> =75A   | -    | 90   | -    | S    |
| Internal Gate Resistance             | R <sub>G(int.)</sub> |  | 3.8  | 4.3  | 5.3  | Ω    |
| Dynamic Characteristics              |                      |  |      |      |      |      |
| Input Capacitance                    | C <sub>iss</sub>     | V <sub>DS</sub> =1000V<br>V <sub>GS</sub> =0V<br>V <sub>AC</sub> =25mV<br>Freq.=100kHz                           | -    | 6550 | -    | pF   |
| Output Capacitance                   | C <sub>oss</sub>     |  | -    | 202  | -    |      |
| Reverse Transfer Capacitance         | C <sub>rss</sub>     |  | -    | 10   | -    |      |
| C <sub>oss</sub> Stored Energy       | E <sub>oss</sub>     |  | -    | 125  | -    | μJ   |
| Turn-On Switching Energy             | E <sub>on</sub>      | V <sub>DD</sub> =800V , V <sub>GS</sub> =-4V/+15V<br>I <sub>D</sub> =75A , R <sub>G(ext)</sub> =2.0Ω<br>L=200μH  | -    | 1050 | -    | μJ   |
| Turn-Off Switching Energy            | E <sub>off</sub>     |  | -    | 350  | -    |      |
| Switching Characteristics            |                      |  |      |      |      |      |
| Turn-On Delay Time                   | t <sub>d(on)</sub>   | V <sub>DS</sub> =800V<br>V <sub>GS</sub> =-4/+15V<br>I <sub>D</sub> =75A<br>R <sub>G(ext)</sub> =2.0Ω<br>L=200μH | -    | 16   | -    | ns   |
| Rise Time                            | t <sub>r</sub>       |  | -    | 37   | -    |      |
| Turn-Off Delay Time                  | t <sub>d(off)</sub>  |  | -    | 67   | -    |      |
| Fall Time                            | t <sub>f</sub>       |  | -    | 13   | -    |      |
| Total Gate Charge                    | Q <sub>g</sub>       | V <sub>DS</sub> =800V  | -    | 235  | -    | nC   |
| Gate to Source Charge                | Q <sub>gs</sub>      | V <sub>GS</sub> =-4/+15V   | -    | 74   | -    |      |
| Gate to Drain Charge                 | Q <sub>gd</sub>      | I <sub>D</sub> =75A  | -    | 73   | -    |      |
| Body Diode Characteristics           |                      |  |      |      |      |      |
| Inverse Diode Forward Voltage        | V <sub>SD</sub>      | V <sub>GS</sub> =-4V , I <sub>SD</sub> =40A<br>T <sub>J</sub> =25°C  | -    | 4.2  | -    | V    |
| Continuous Diode Forward Current     | I <sub>S</sub>       | V <sub>GS</sub> =-4V , T <sub>J</sub> =25°C  | -    | 128  | -    | A    |
| Reverse Recovery Time                | T <sub>rr</sub>      | V <sub>GS</sub> =-4V   | -    | 25   | -    | ns   |
| Reverse Recovery Charge              | Q <sub>rr</sub>      | I <sub>SD</sub> =75A , V <sub>DS</sub> =800V,<br>di/dt=2400A/μs  | -    | 670  | -    | nC   |
| Peak Reverse Recovery Current        | I <sub>rrm</sub>     | T <sub>J</sub> =25°C   | -    | 45   | -    | A    |
| Thermal Resistance                   |                      |  |      |      |      |      |
| Thermal Resistance, Junction-to-Case | R <sub>θJC</sub>     |  | -    | 0.21 | 0.23 | °C/W |

## Typical Performance

Fig 1. Output Characteristics,  $T_J = -40^\circ\text{C}$

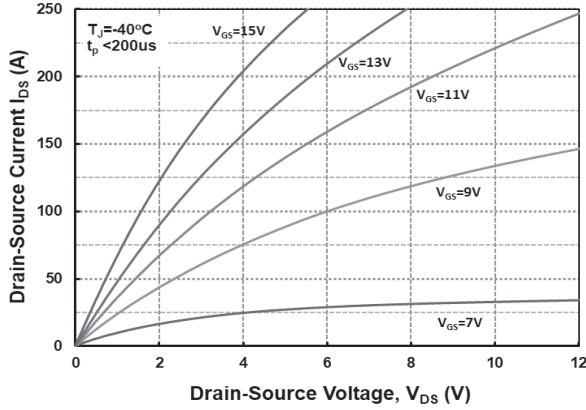


Fig 2. Output Characteristics,  $T_J = 25^\circ\text{C}$

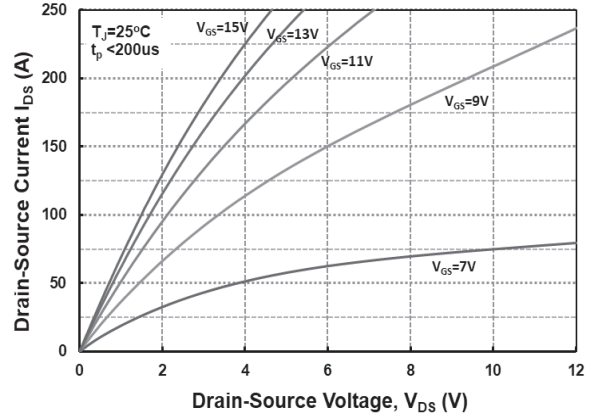


Fig 3. Output Characteristics,  $T_J = 175^\circ\text{C}$

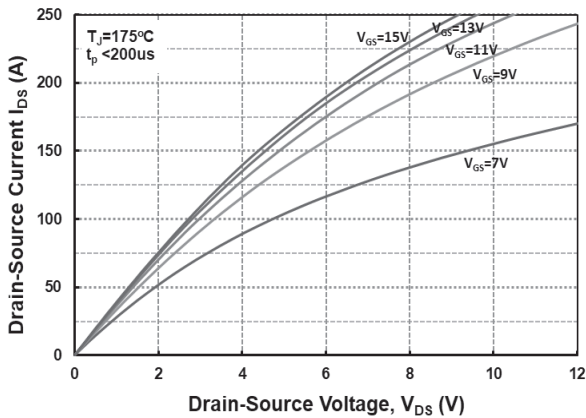


Fig 4. Normalized On-Resistance vs. Temperature

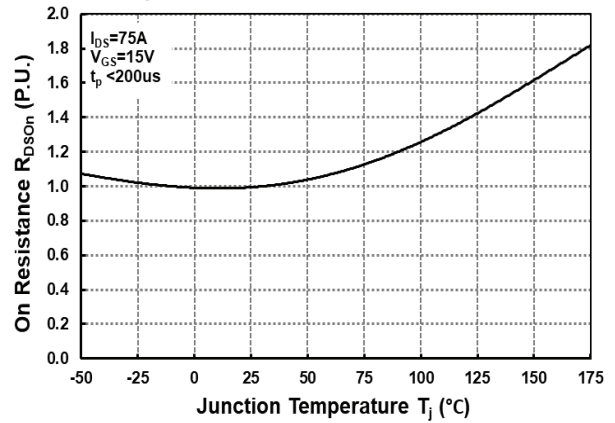


Fig 5. On-Resistance vs. Drain Current for Various Temperatures

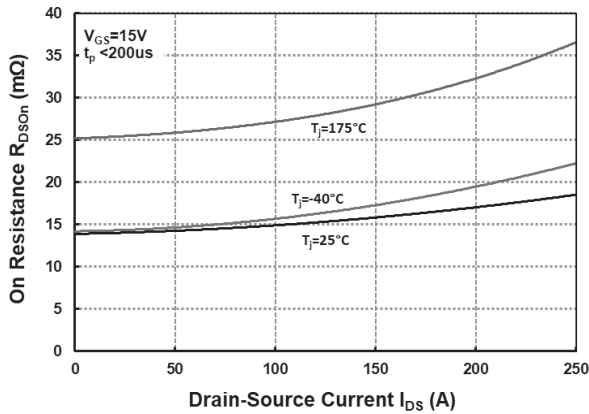
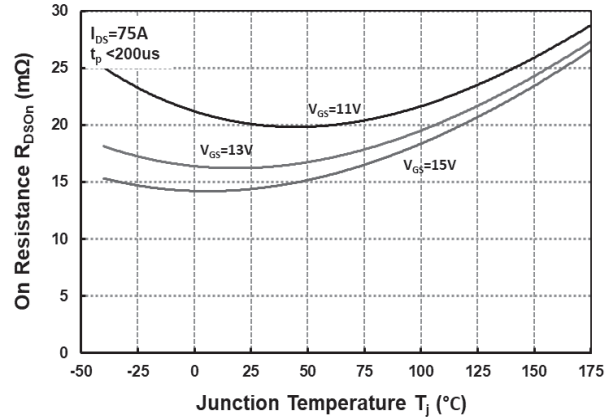
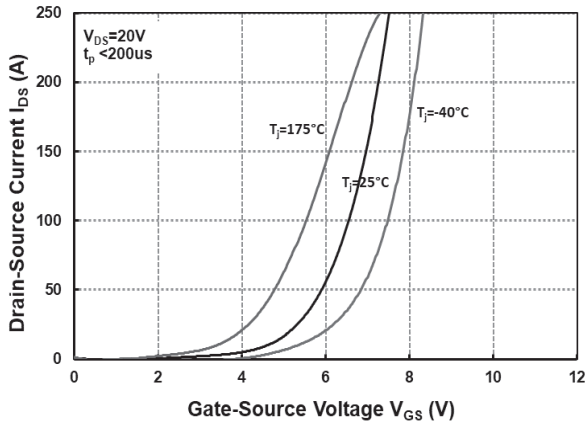


Fig 6. On-Resistance vs. Temperature for Various Gate Voltage

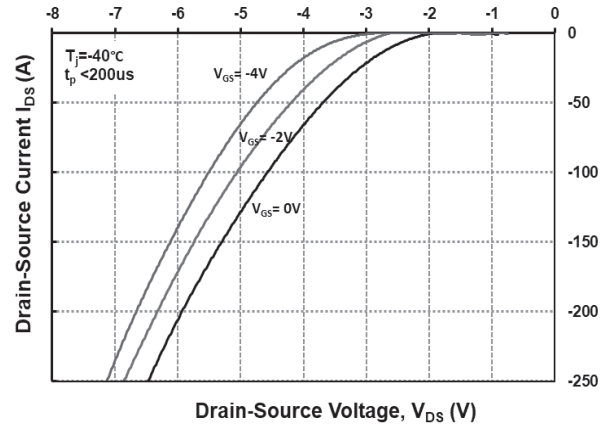


## Typical Performance

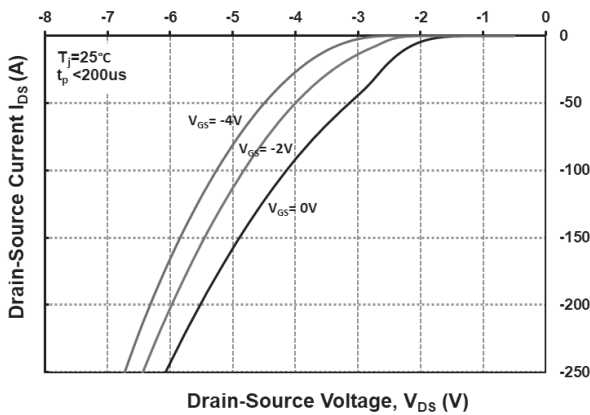
**Fig 7. Transfer Characteristic for Various Junction Temperatures**



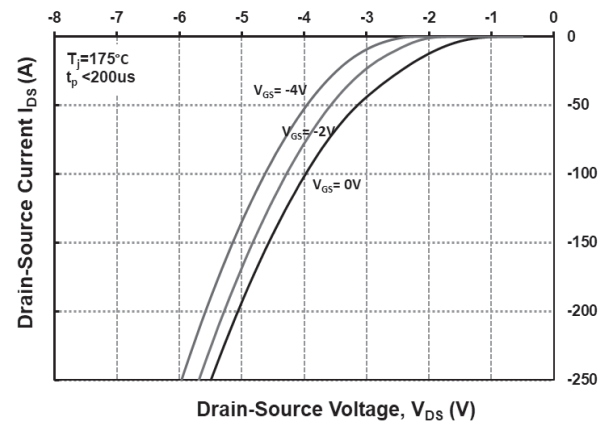
**Fig 8. Body Diode Characteristics @  $-40^\circ C$**



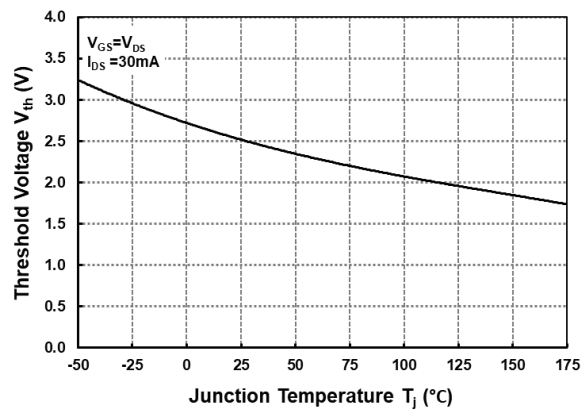
**Fig 9. Body Diode Characteristics @  $25^\circ C$**



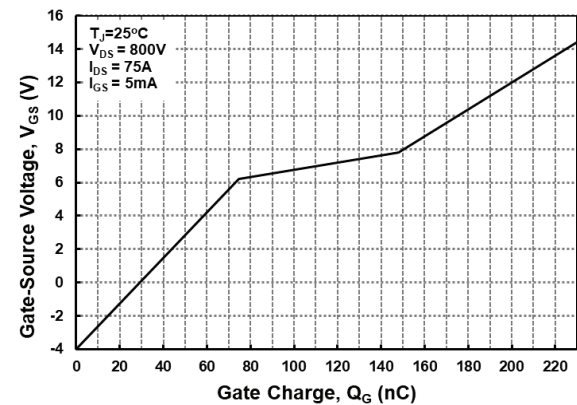
**Fig 10. Body Diode Characteristics @  $175^\circ C$**



**Fig 11. Threshold Voltage vs. Temperature**



**Fig 12. Gate Charge Characteristics**



## Typical Performance

Fig 13. 3<sup>rd</sup> Quadrant Characteristics @ -40°C

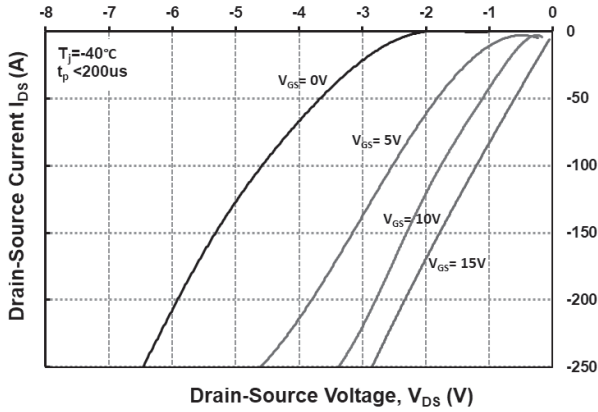


Fig 14. 3<sup>rd</sup> Quadrant Characteristics @ 25°C

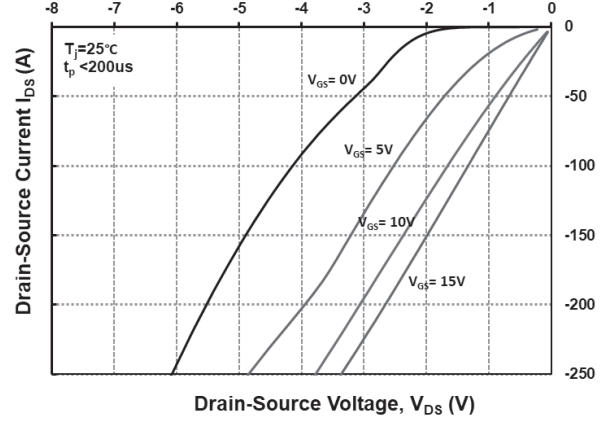


Fig 15. 3<sup>rd</sup> Quadrant Characteristics @ 175°C

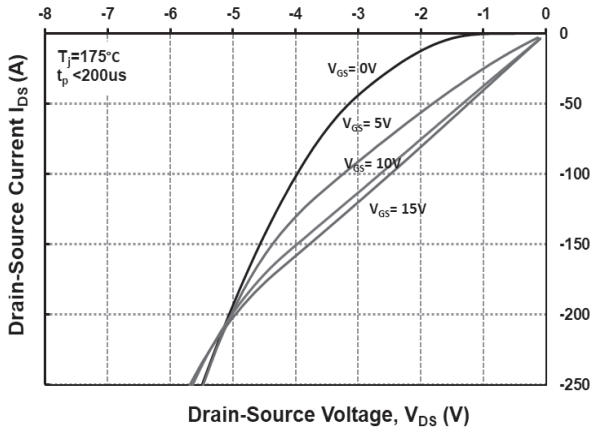


Fig 16. Output Capacitor Stored Energy

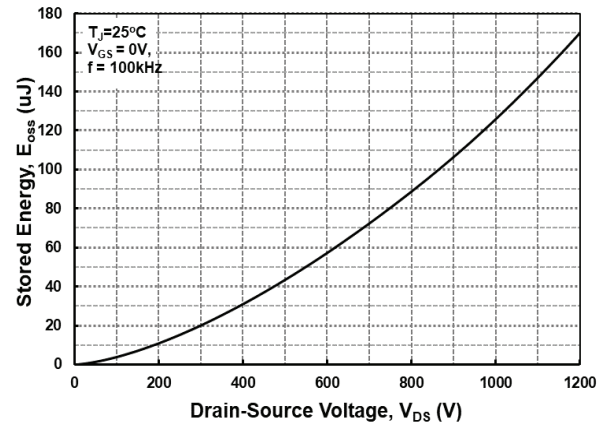


Fig 17. Capacitances vs. Drain-Source Voltage (0-200V)

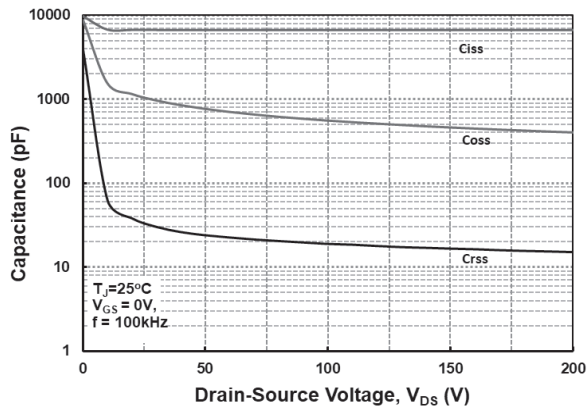
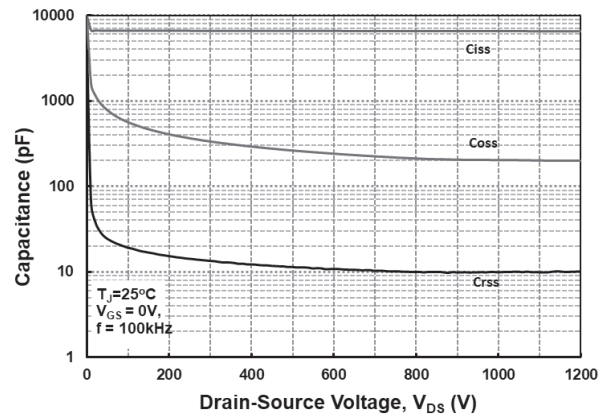


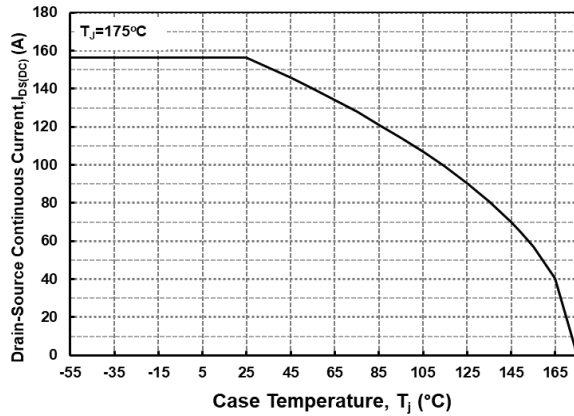
Fig 18. Capacitances vs. Drain-Source Voltage (0-1200V)



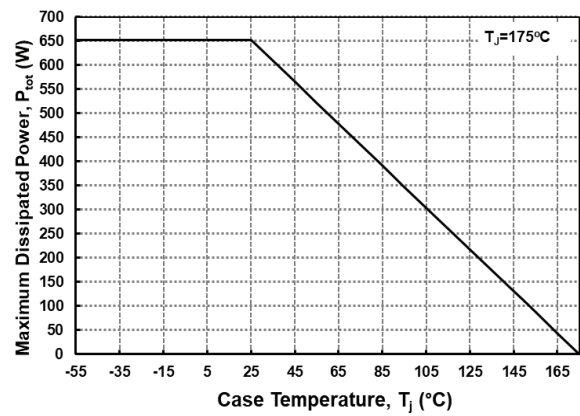


## Typical Performance

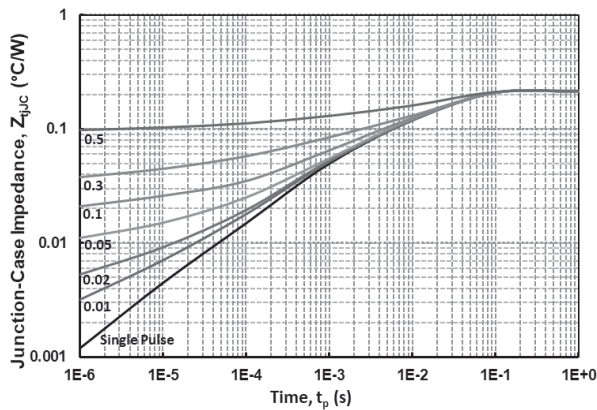
**Fig 19. Continuous Drain Current Derating vs. Case Temperature**



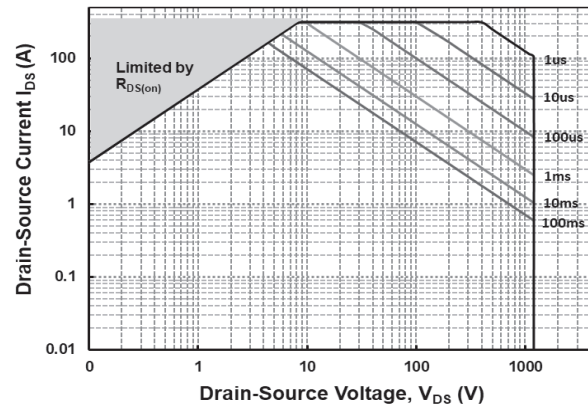
**Fig 20. Maximum Power Dissipation Derating vs. Case Temperature**



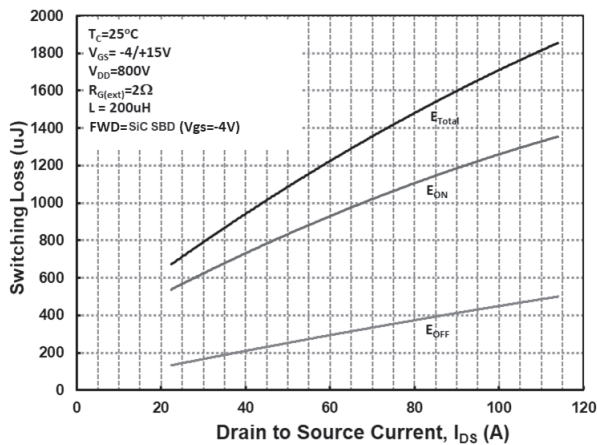
**Fig 21. Transient Thermal Impedance (Junction – Case)**



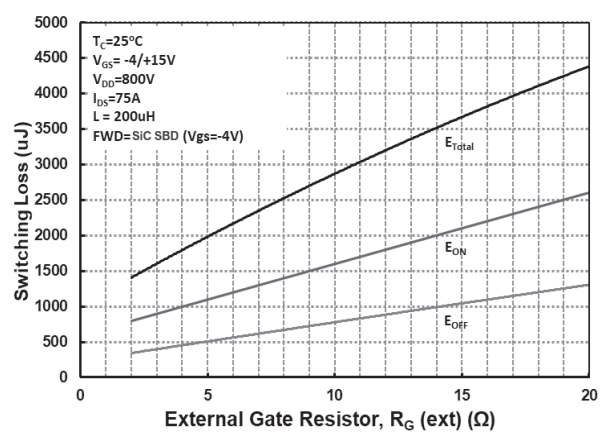
**Fig 22. Safe Operating Area**



**Fig 23. Clamped Inductive Switching Energy vs Drain Current ( $V_{DD} = 800\text{V}$ )**

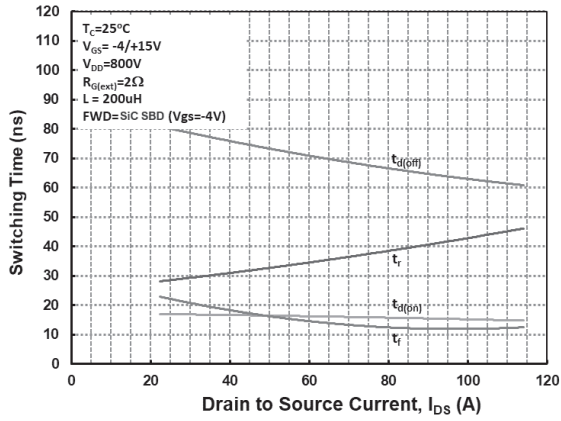


**Fig 24. Clamped Inductive Switching Energy vs External Gate Resistor  $R_{G(ext)}$**

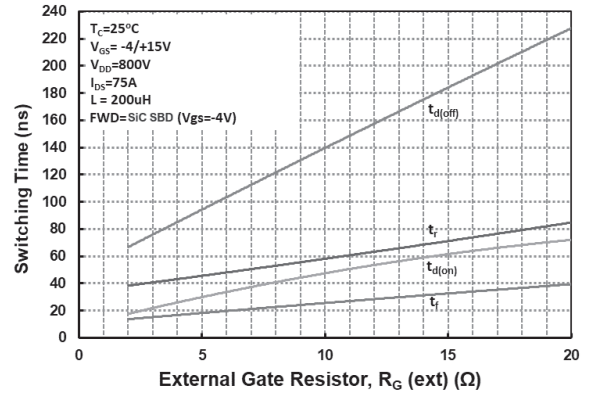


## Typical Performance

**Fig 25. Switching Times vs Drain Current**  
( $V_{DD} = 800V$ )



**Fig 26. Switching Times vs External Gate Resistor  $R_{G(ext)}$**



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